Listing of Claims:

1. (Currently amended) A light-emitting diode chip having an epitaxial semiconductor layer sequence with an active zone that emits electromagnetic radiation and an electrical contact structure comprising:

a radiation-transmissive electrical current expansion layer, which contains ZnO[[,]]; and

an electrical connection layer[[,]];

wherein the current expansion layer <u>is applied on a cladding layer of the</u> <u>semiconductor layer and</u> comprises a window, in which the connection layer is applied on [[a]] said cladding layer of the semiconductor layer sequence;

the connection layer is electrically conductively connected to the current expansion layer; and

the wherein a junction between the connection layer and the cladding layer, during the operation of the light-emitting diode chip, is not electrically conductive or is only so poorly electrically conductive <u>such</u> that the <u>an</u> entire, or virtually the entire, current <u>from the connection layer</u> flows via the current expansion layer into the semiconductor layer sequence.

2. (Original) The light-emitting diode chip according to claim 1, wherein

the connection layer comprises a metal and the junction between the connection layer and the cladding layer comprises an electrical potential barrier.

3. (Currently amended) The light-emitting diode chip according to claim 1, wherein

the <u>a</u> sheet resistance of intermediate layers of the semiconductor layer sequence between the active zone and the electrical contact structure is in each case greater than or equal to 200 Ω /sq.

4. (Currently amended) The light-emitting diode chip according to claim 1, wherein

the current expansion layer comprises a sheet resistance of less than or equal to 190 Ω/sq , preferably of less than or equal to 30 Ω/sq .

5. (Currently amended) The light-emitting diode chip according to claim 1, wherein

the connection layer extends beyond the window on that <u>a</u> side of the current expansion layer which is remote from the semiconductor layer sequence and is applied to the <u>a</u> front-side surface of the current expansion layer in such a way that it so as to partly eovers cover the latter current expansion layer and so that the junction between the connection layer and the current expansion layer is electrically conductive in this region.

- 6. (Original) The light-emitting diode chip according to claim 1, wherein the semiconductor layer sequence is based on $In_xGa_yAl_{1-x-y}P$, $In_xGa_yAl_{1-x-y}As$, $In_xGa_yAl_{1-x-y}N$ or $In_xGa_yAs_{1-x-y}P$, where $0 \le x \le 1$, $0 \le y \le 1$ and $x + y \le 1$.
- 7. (Currently amended) The light-emitting diode chip according to claim 1, wherein the cladding layer comprises $Al_xGa_{1-x}As_yP_{1-y}$, where $0 \le x \le 1$, and $0 \le y \le 1$ [[,]] preferably where $0.1 \le x \le 0.5$ and y = 1 or where x = 0 and y = 0.
- 8. (Currently amended) The light-emitting diode chip according to claim 7, wherein the cladding layer is p-doped[[,]] with at least one of a the dopant Zn and/or and C.
- 9. (Currently amended) The light-emitting diode chip according to claim 1, wherein the cladding layer is doped with a dopant concentration of between about 5.10¹⁹, in particular between about 1.10¹⁸ and about 1.10¹⁹, the limits being included in each case.

10. (Original) The light-emitting diode chip according to claim 1, wherein the current expansion layer comprises Al.

11. (Currently amended) The light-emitting diode chip according to claim 10, wherein

the <u>a</u> proportion of Al in the current expansion layer <u>lies</u> is in a range of between 0% and 10% inclusive, preferably between 1% inclusive and 3% inclusive.

12. (Currently amended) The light-emitting diode chip according to claim 1, wherein

the current expansion layer has a thickness of between 100 and 600 nm, <u>inclusive</u> in particular between 450 and 550 nm, the limits being included in each case.

13. (Currently amended) The light-emitting diode chip according to claim 1, wherein

the current expansion layer has a thickness corresponding to about a quarter of the \underline{a} wavelength of a radiation emitted by the light-emitting diode chip.

14. (Currently amended) The light-emitting diode chip according to claim 1, wherein

the current expansion layer is provided with watertight material in such a way that it the current expansion layer is adequately protected against moisture.

15. (Currently amended) The optoelectronic light-emitting diode chip component according to claim 14,

wherein

watertight material is applied to free areas of the contact layer.

16. (Currently amended) The optoelectronic light-emitting diode chip component according to claim 15,

wherein

watertight material is applied to all the free areas of the contact layer.

17. (Currently amended) The light-emitting diode chip according to claim 14,

wherein

the watertight material is a dielectric that is transparent to an the electromagnetic radiation emitted by the light-emitting diode chip.

18. (Original) The light-emitting diode chip according to claim 17,

wherein

the dielectric comprises one or more of the substances Si_xN_y , SiO_x , SiO_y , SiO_y , and SiO_xN_y .

19. (Currently amended) The light-emitting diode chip according to claim 14, wherein

the <u>a</u> refractive index of the watertight material is less than the refractive index of the current expansion layer and is adapted <u>so as</u> to <u>significantly minimize</u> the <u>greatest possible extent in</u> particular for a minimization of reflections of the radiation emitted by the light-emitting diode chip at interfaces with respect to the watertight material.

20. (Currently amended) The light-emitting diode chip according to claim 14, wherein

the current expansion layer has a thickness corresponding to about an integer multiple of half the <u>a</u> wavelength of [[a]] <u>the</u> radiation emitted by the light-emitting diode chip, and the watertight material has a thickness corresponding to about a quarter of said wavelength.

21. (Currently amended) The light-emitting diode chip according to claim 14, wherein

the thickness of the watertight material lies is in a range of between 50 inclusive and 200 nm, inclusive.

22. (New) The light-emitting diode chip according to claim 4, wherein the sheet resistance is less than or equal to $30 \Omega/\text{sq}$.

23. (New) The light-emitting diode chip according to claim 7, wherein

the cladding layer comprises $Al_xGa_{1-x}As_yP_{1-y}$, where $0.1 \le x \le 0.5$, and y=1 or where x=0 and y=0.

- 24. (New) The light-emitting diode chip according to claim 9, wherein the dopant concentration is between about 1 10 18 and 1 10 19, inclusive.
- 25. (New) The light-emitting diode chip according to claim 11, wherein the proportion of A1 is in a range of between 1% and 3%, inclusive.
- 26. (New) The light-emitting diode chip according to claim 12, wherein the thickness of the current expansion layer is between 450 and 550 nm, inclusive.